

<b>Notice of References Cited</b>	Application/Control No. 10/572,752		Applicant(s)/Patent Under Reexamination NAKAMURA ET AL.	
	Examiner JENNIFER F. CHANG		Art Unit 2821	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,400,330 B1	06-2002	Maruyama et al.	343/788
*	B	US-6,400,338 B1	06-2002	Mejia et al.	343/873
*	C	US-2003/0184489 A1	10-2003	Maruyama et al.	343/788
*	D	US-6,795,032 B2	09-2004	Ieda et al.	343/713
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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